

SAMSUNG

OPERATION TEST REPORT ON TDK CERAMIC RESONATOR

(FCR10.0MC5)

IC S3F84BBXZZ (SAMSUNG)

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APPROVED	CHECKED	CHECKED
I.Katoh		

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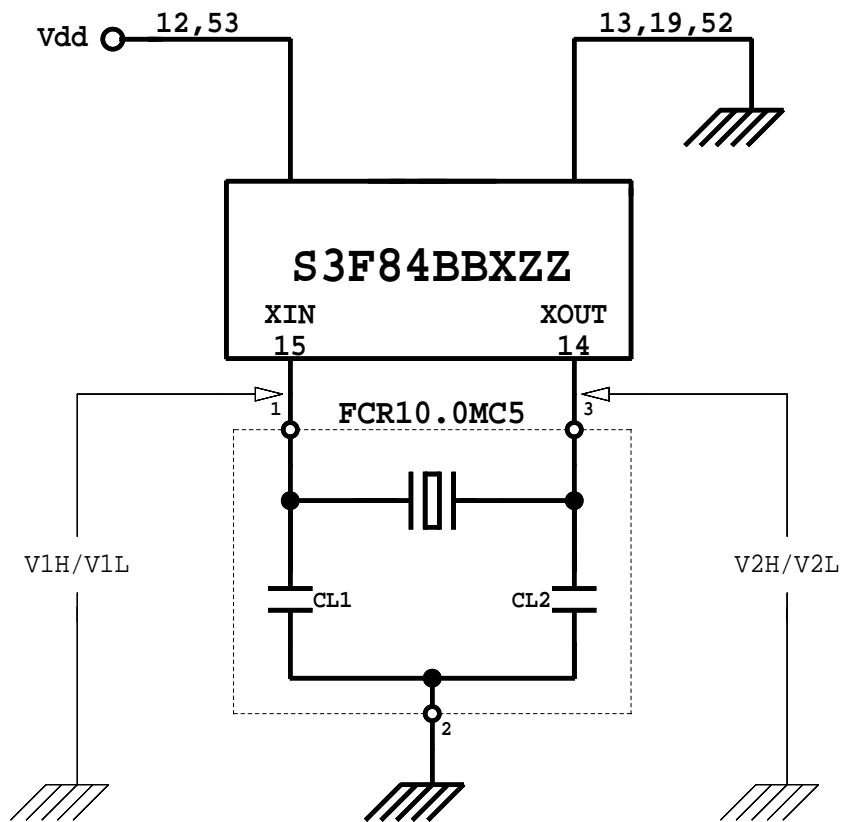
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## 2.Conclusions

We could confirm the operation satisfactory under  
the following test conditions.

### Test Conditions

IC	: S3F84BBXZZ (SAMSUNG)
Ceramic Resonator	: FCR10.0MC5 (Typical and worst sample are tested)
Power Supply Voltage	: 2.7(V) ~ 5.5(V)
Temperature Range	: -25(°C) ~ 85(°C)

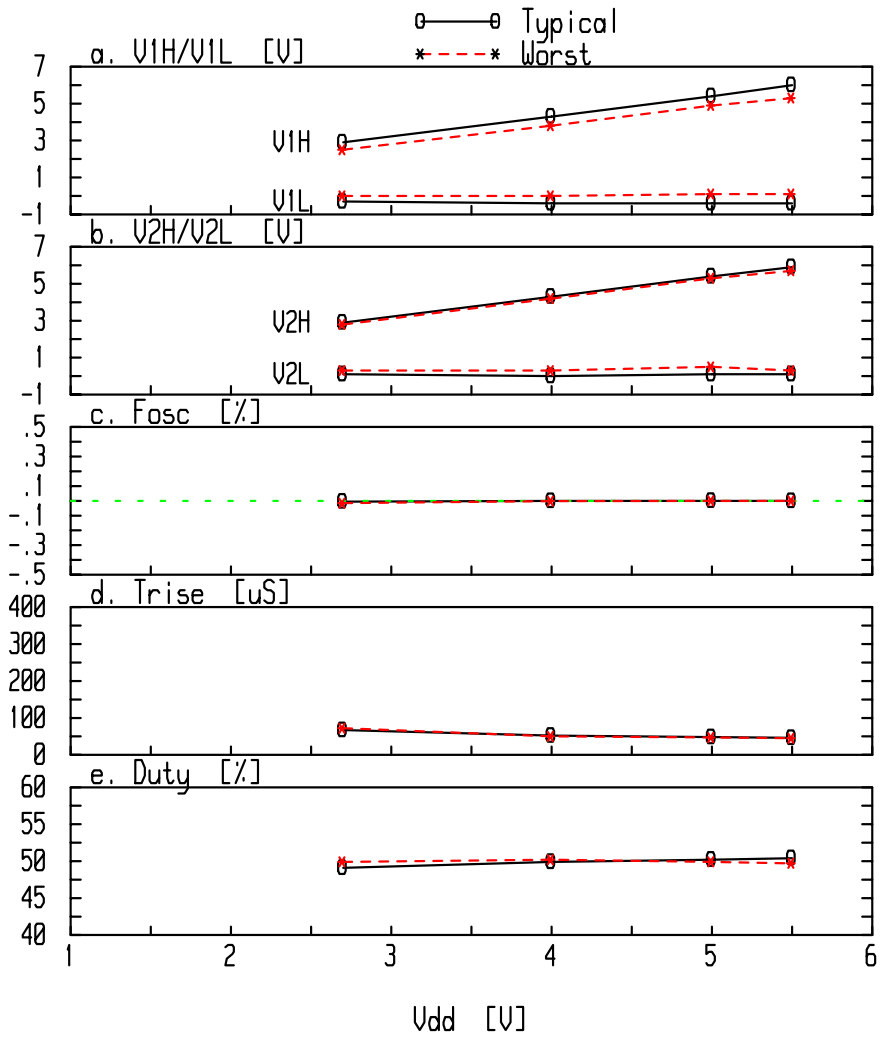


\*BUILT-IN LOADING CAPACITOR  
 CL1/CL2=20/20pF +/-20%

Oscillating circuit for evaluation

S3F84BBXZZ - 1

FCR10.0MC5  
Ta= 20 [deg]



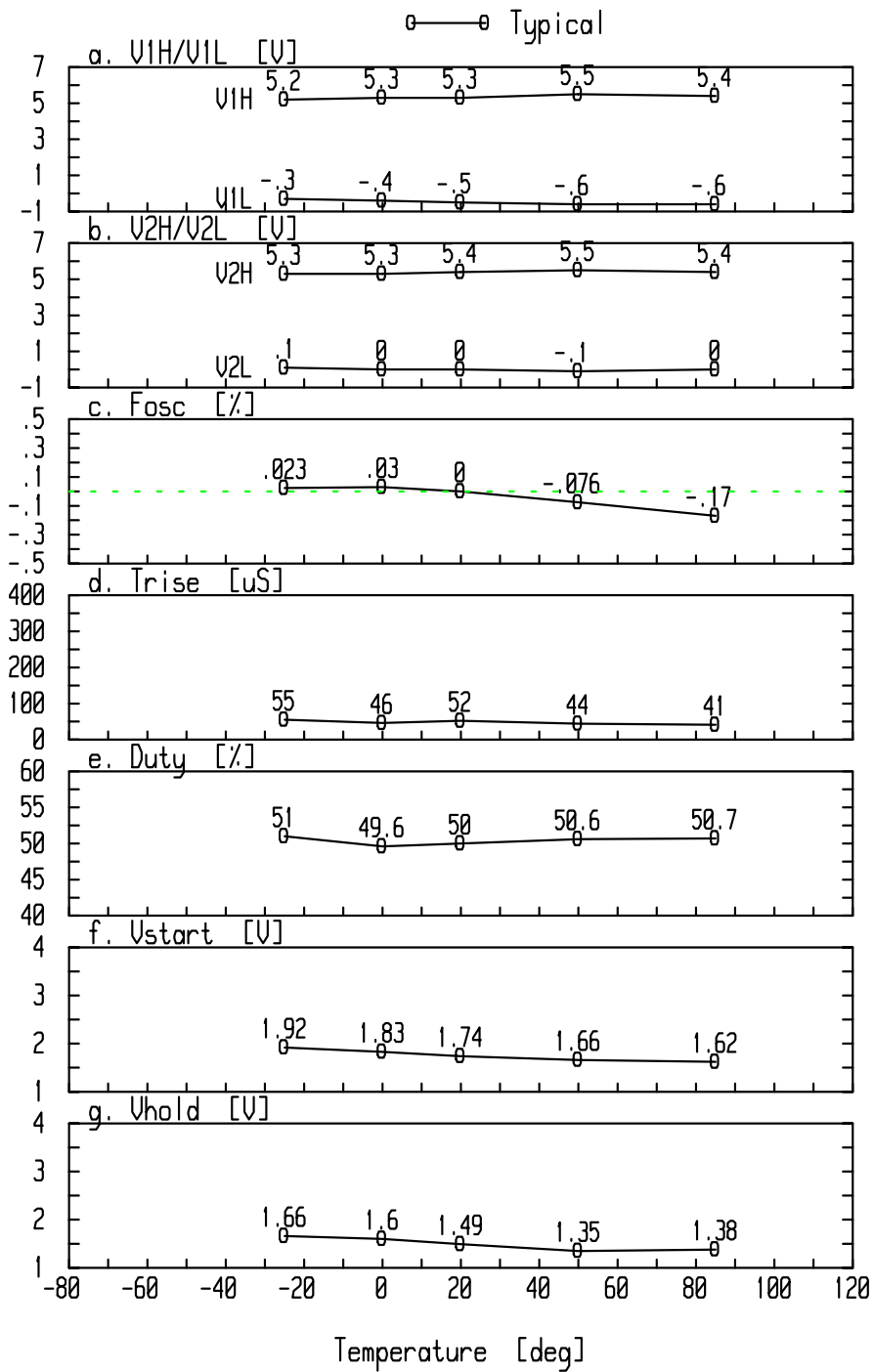
f. Ustart [V]  
Typical = 1.77  
Worst = 1.86

g. Uhold [V]  
Typical = 1.5  
Worst = 1.75

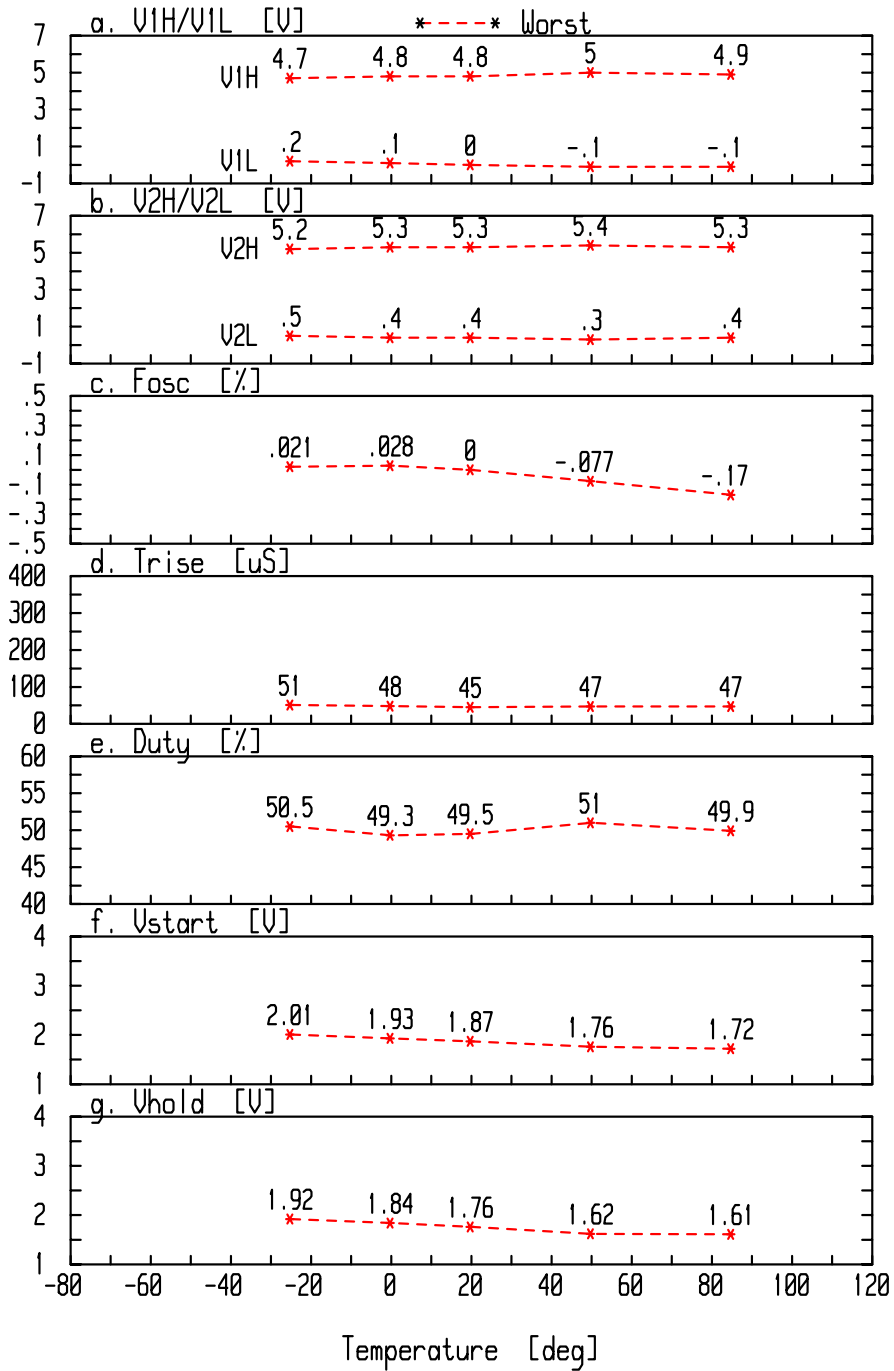
Power supply voltage dependence of oscillating characteristics

S3F84BBXZZ - 1

FCR10.0MC5  
 $V_{dd} = 5$  [V] (Fig. a~e)



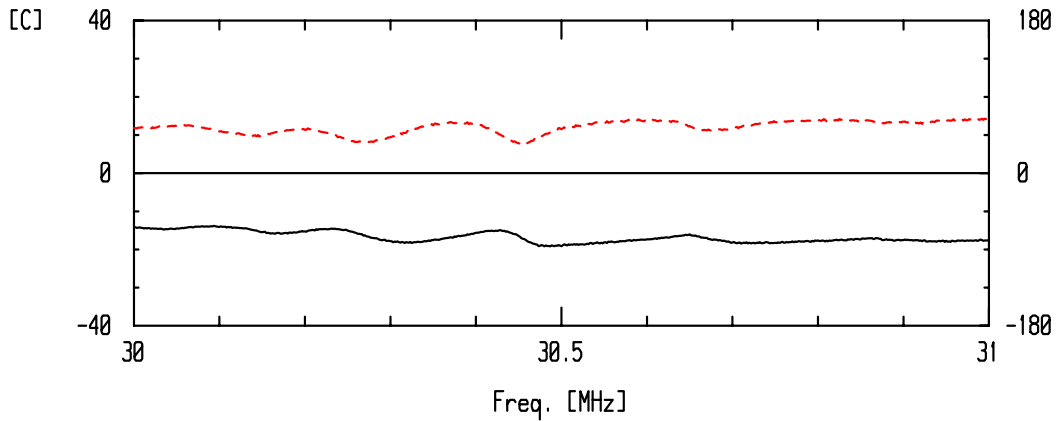
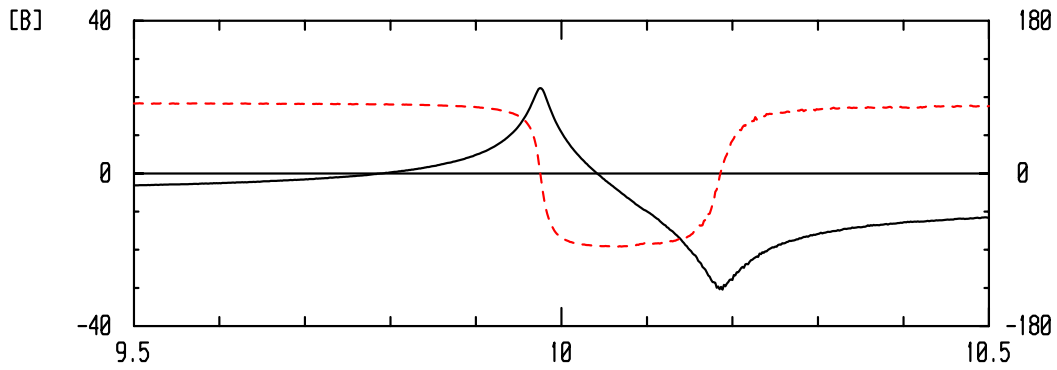
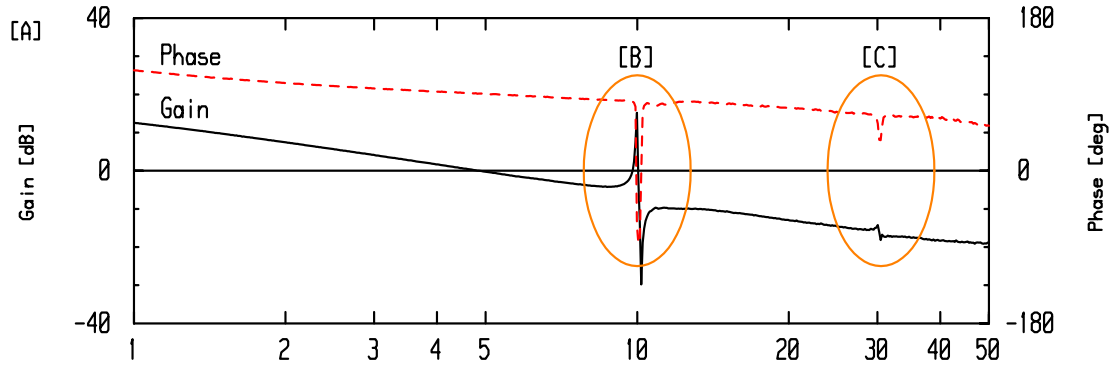
Temperature dependence of oscillating characteristics



Temperature dependence of oscillating characteristics

S3F84BBXZZ - 1  
 FCR10.0MC5 - Typical  
 Vdd [V] 5

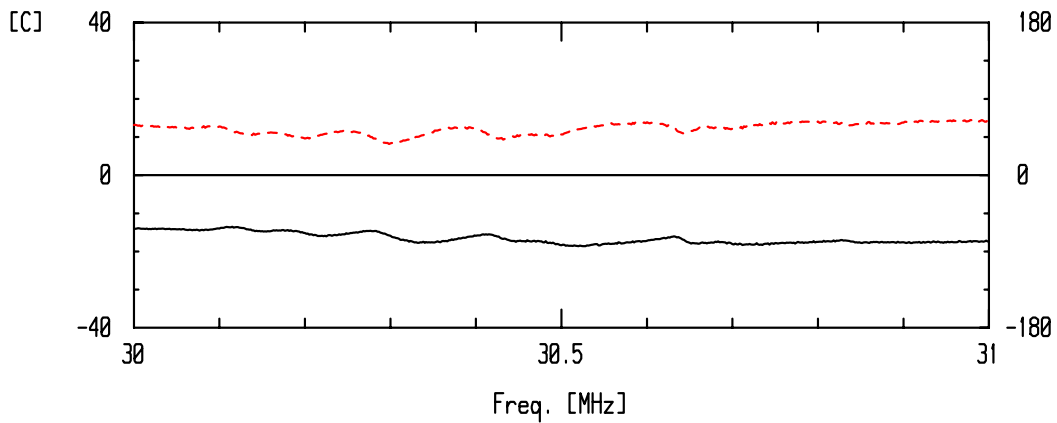
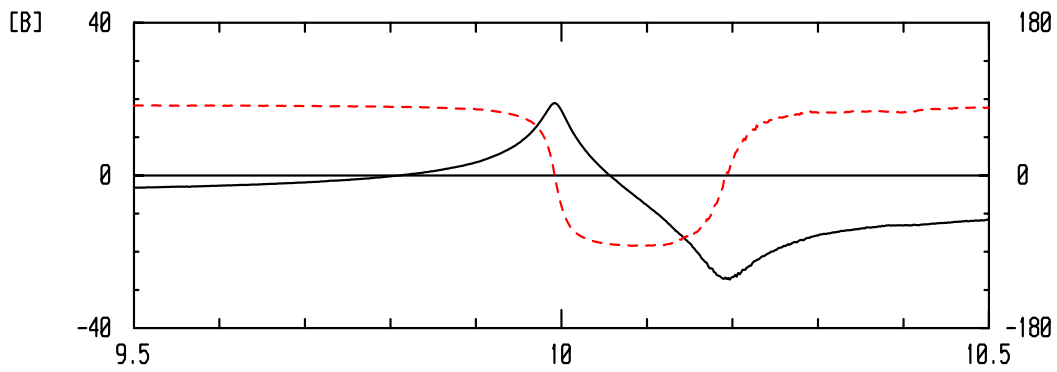
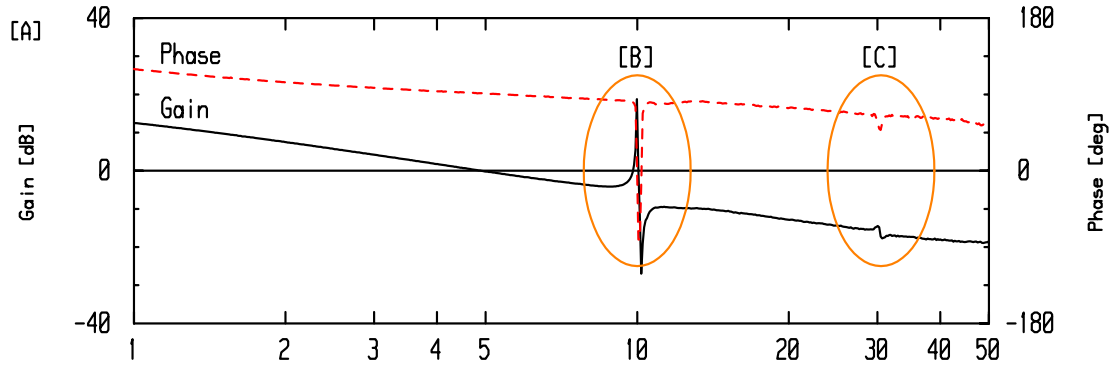
	[B]	[C]
Gmax [dB]	22.4	-13.82
LGM [dB]	22.31	0
FLGM [MHz]	9.9762	0
LPM [deg]	-85.39	43.34



Open loop characteristics (Typical Sample)

S3F84BBXZZ - 1  
 FCR10.0MC5 - Worst  
 Vdd [V] 5

	[B]	[C]
Gmax [dB]	18.97	-13.5
LGM [dB]	18.91	0
FLGM [MHz]	9.993	0
LPM [deg]	-81.1	46.96



Open loop characteristics (Worst Sample)